## Notice of References Cited Application/Control No. 10/591,529 Examiner SUNG H. PAK Applicant(s)/Patent Under Reexamination INOUE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-7,304,780	12-2007	Liu et al.	359/245	
*	В	US-7,236,220	06-2007	Kim et al.	349/106	
*	С	US-6,600,470	07-2003	Tsuda, Atsunari	345/89	
	D	US-				
	Е	US-				
	F	US-				
	G	US-				
	Н	US-				
	I	US-				
	J	US-				
	K	US-				
	L	US-				
	М	US-				

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	х					

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